SpectraStar™ XT-F

WHEAT AND FLOUR ANALYZER PACKAGE

KPM

Flour, Wheat and Wheat By-Products Analyzer

The SpectraStar™ XT-F is a complete analyzer package for the rapid analysis of flour, wheat and by-products at-line or in a quality laboratory.

PROVEN TECHNOLOGY

The SpectraStar™ XT-F analyzer uses a scanning monochromator and proven near-infrared (NIR) technology to deliver highly accurate results for both millers and bakers. NIR analyzers are trusted daily in thousands of locations to measure key parameters and contribute to quality control.

READY TO USE WITH SAMPLE CUPS AND CALIBRATIONS

The SpectraStar™ XT-F analyzer package is complete with the sample accessories and calibrations needed for millers and bakers. For whole wheat kernels, protein and moisture calibrations ensure incoming wheat quality and monitor tempering processes. For finished flour, NIR calibrations for moisture, protein, and ash provide essential information for routine quality control and regulatory compliance. These calibrations help millers and bakers ensure consistent flour quality and meet product specifications with confidence.

EASY IMPLEMENTATION AND OPERATION

Based on stand-alone design, the SpectraStar™ XT-F is a plug and play analyzer that will easily fit into almost any analytical situation. The sealed case and touch screen display are ideal for dusty environments like flour mills and raw material receiving areas. Advanced sample management and reporting features mean that this analyzer is also ready for the quality laboratory. The SpectraStar™ XT-F is operated by UScan™, a software package incorporating an intuitive graphical interface and a reliable SQL database for data management. Designed for ease of use, UScan has a minimal training requirement and routine operators can be completely trained in 15 minutes to deliver accurate, operator-independent results.

APPLICATIONS

- Test incoming wheat quality
- Monitor tempering process
- Evaluate process streams to ensure optimal milling conditions
- Monitor ash content to optimize extraction and increase production
- Validate final flour quality
- Test quality of milling by-products

SPECTRASTAR™ XT-F FEATURES:

- Touch screen interface
- Intuitive graphical software
- Single sample results, history or SPC Chart sample views
- Operator-independent results

KPMLink®

CLOUD-BASED MANAGEMENT SOFTWARE

KPMLink® makes it easy to ensure all SpectraStar analyzers within your organization are operating at exact standards and at consistent configurations, regardless of location or local expertise.

Scan to learn more about KPMLink®.

ORDERING INFORMATION

The SpectraStar™ XT-F is an analyzer package with the sample accessories and calibrations needed by millers and bakers. Calibrations include: whole wheat kernels (moisture and protein), ground wheat, bran, midds and red dog (moisture, protein and fiber), finished flour (moisture, protein, ash).

Part Number	Description
US-SPSR-XTF	SpectraStar™ XT-F NIR Analyzer including monochromator, rotating top window configuration, built in Windows 10 computer with 17" touch screen, UScan software, WiFi dongle, multi-cup adapter, ring cup/powder cup ring, large open cup with plunger and sample ring, and TAS Standards. Calibrations for whole wheat kernels, ground wheat and by-products, and finished flour

CALIBRATION OPTIONS

Part Number	Description
US-CALB-1000	Additional Unity calibration for single product type, moisture, protein, and/or oil. See separate list for products available.

ACCESSORIES

A variety of sample and software accessories are available

Part Number	Description
US-LGOP-0001	Large open cup with plunger
US-RTIR-0016	Large open cup sample ring
US-SRCP-0025A	Small round cup, 25 mm height
US-ISIH-0307	Ring cup
KPMLink-0001	One (1) year of KPMLink® User License and one Instrument License, access to training course via the KPM Academy for one user.
KPMLink-0002	Additional KPMLink® User License
EM-10	Moisture Oven for Reference Measurement

SPECIFICATIONS

Light source	Tungsten halogen lamp with MTBF rating of 10,000 hours, user changeable
Measurement mode	Reflectance
Detector	High performance ultra-cooled InGaAs extended range detector
Optical bandwidth	10.0 ± 0.3 nm actual FWHM
Absorbance range	Up to 3 AU
Analysis time	10 – 60 sec.
Wavelength accuracy	< 0.02 nm to traceable standard reference material
Wavelength precision	< 0.005 nm
Wavelength range	1400 - 2600 nm
Number of data points	1200
Photometric noise full range	< 20 µAu
Instrument case	Powder coated aluminum, completely sealed, no venting or fan
ISO 12099 compliant	Animal feedstuffs, cereals and milled cereal products - Guidelines for the application of near infrared spectrometry
Built-in computer	Windows 10 Professional, SSD
Networking	LIMS compatible, HDMI port, 4 USB ports
Ambient temperature	1 - 40°C
Ambient humidity	< 95% RH, < 85% RH recommended

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